

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of Applicants:

Beaman et al.

Serial No.: 09/382,834

Filed: August 25, 1999

For: HIGH DENSITY INTEGRATED CIRCUIT APPARATUS,  
TEST PROBE AND METHODS OF USE THEREOF

Date: June 25, 2008

Group Art Unit: 2829

Examiner: V. P. Nguyen

Docket No.: YO993-028BX

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT**

Sir:

In response to Office Action dated May 14, 2008, please consider the following:

Amendments to the claims begin on page 2 of this paper.

Remarks begin on page 35 of this paper.